

Notice of References Cited	Application/Control No. 10/647,540	Applicant(s)/Patent Under Reexamination NAPHADE ET AL.	
	Examiner ALEX LIEW	Art Unit 2624	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,970,860	11-2005	Liu et al.	707/3
	B	US-			
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	D	US-			
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	K	US-			
	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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